

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S161	0	((built-in-self-test (built-in adj self-test) BIST ("first logic" adj (module section circuit device))) and (interface JTAG "boundary scan" ("second logic" adj (modulesection circuit device))) and (((("third logic" adj (module section circuit device)) multiplex\$3 switch\$3) with (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))). clm.	US-PGPUB	OR	ON	2008/04/11 14:49
S160	1	(built-in-self-test (built-in adj self-test) BIST ("first logic" adj (module section circuit device))) and (interface JTAG "boundary scan" ("second logic" adj (modulesection circuit device))) and (((("third logic" adj (module section circuit device)) multiplex\$3 switch\$3) with (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:47

S159	1	(built-in-self-test (built-in adj self-test) BIST ("first logic" adj (section circuit device))) and (interface JTAG "boundary scan" ("second logic" adj (section circuit device))) and (((("third logic" adj (section circuit device)) multiplex\$3 switch\$3) with (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:32
S158	13	(built-in-self-test (built-in adj self-test) BIST "first logic") and (interface JTAG "boundary scan" "second logic") and (((("third logic" multiplex\$3 switch\$3) with (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:26
S157	44	(built-in-self-test (built-in adj self-test) BIST) and (interface JTAG "boundary scan") and (((multiplex\$3 switching (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control near2 signal))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:16
S156	128	(built-in-self-test (built-in adj self-test) BIST) and (interface JTAG "boundary scan") and (((multiplex\$3 switching (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control))) and (\$2RAM memory SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:15

S155	128	((built-in-self-test (built-in adj self-test) BIST) and (interface JTAG "boundary scan") and (multiplex\$3 switching (select\$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control)) and (\$2RAM memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:09
S154	1	((built-in-self-test (built-in adj self-test) BIST) same (interface JTAG "boundary scan") same (multiplex\$3 switching (select \$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) near2 (control)) same (\$2RAM memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:07
S153	68	((built-in-self-test (built-in adj self-test) BIST) same (interface JTAG "boundary scan") same (multiplex\$3 switching (select \$5 near3 (connect\$3 coupl\$3))) with ((two plurality several multiple) (control)) same (\$2RAM memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:06
S152	5	((built-in-self-test (built-in adj self-test) BIST) same (interface JTAG "boundary scan") same (multiplex\$3 switching (select \$5 near3 (connect\$3 coupl\$3))) same (\$2RAM memory)) same (SUT DUT CUT ((device chip circuit system) adj under adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 10:01
S151	125	((built-in-self-test (built-in adj self-test) BIST) same (interface JTAG "boundary scan") same (multiplex\$3 switching (select \$5 near3 (connect\$3 coupl\$3))) same (\$2RAM memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/11 09:59
S150	0	09/933468	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/10 18:43

S149	71	S148 and ("built-in-self-test" "built-in\$1self-test" BIST "self-test") and ((inject\$3 insert \$3 transmit\$4) near4 (fault error "bad bit"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/10 17:08
S148	12754	(714/710,711,718,719,733 365/200,201). ccs.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/10 17:07
S147	7	S145 and (control near3 signal near3 (inactiv \$4 unassert\$3 "not assert\$3"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/09 19:31
S146	0	S145 and (one near4 control near3 signal near3 (inactiv\$4 unassert\$3 "not assert\$3"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/09 19:31
S145	107	((two both) near4 control near3 signal near3 (activ\$4 assert\$3)) with (multiplx\$3 switch \$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/09 19:30
S143	188	((two both) near4 control near3 signal near3 (activ\$4 assert\$3)) same (multiplx\$3 switch \$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/09 19:29

S141	0	(both near4 control near3 signal near3 (activ\$4 assert\$3)) same (multiplx\$3 switch\$3) and (one near4 control near3 signal near3 (inactiv\$4 unassert\$3 "not assert\$3")) same (multiplx\$3 switch\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/09 19:29
S139	1	"5301296".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:38
S138	1	"5740412".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:37
S137	1	"5781721".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:37
S136	1	"6001662".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:37
S135	1	"6101578".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:36
S134	1	"6115789".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:36
S133	1	"6145055".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:35
S132	1	"6351789".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:35
S131	1	"6658611".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:35
S130	1	"6732234".PN.	USPAT; USOCR	OR	ON	2007/08/14 13:34
S129	86	("built-in-self-test" "built-in\$1self-test" BIST "self-test") same ((two plurality multipl\$7) near3 "control signal" with (multiplex\$3 selector switch))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/14 11:24

S128	550	("built-in-self-test" "built-in\$1self-test" BIST "self-test") and ((two plurality multipl\$7) near3 "control signal" with (multiplex\$3 selector switch))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/14 11:24
S127	5	S126 and (JTAG with (controller host processor)) and ((two plurality multiple) near3 control with (multiplex\$3 select\$3 switch\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/14 11:22
S126	1544	("built-in-self-test" "built-in\$1self-test" BIST "self-test") and (714/710,711,718,719,733,734 365/200,201).cls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/14 11:22
S125	73	S124 and (JTAG with (controller host processor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/14 11:15
S124	1402	("built-in-self-test" "built-in\$1self-test" BIST "self-test") and (714/710,711,718,719,733,734 365/200,201).cls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 16:14
S98	115	S97 and (714/710,711,718,719,733 365/200,201).cls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 16:14

S97	2159	(JTAG with (controller host processor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/24 16:14
S123	1	"5388104".PN.	USPAT; USOCR	OR	ON	2007/01/24 12:00
S122	1	"5471482".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:59
S121	1	"5572712".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:43
S120	1	"5633877".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:42
S119	1	"5661732".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:41
S118	1	"5668817".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:41
S117	1	"5680543".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:41
S116	1	"5737340".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:41
S115	1	"5784323".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:40
S114	1	"5831992".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:39
S113	1	"5938784".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:30
S112	1	"6032281".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:21
S111	1	"6108798".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:20

S110	1	"6658611".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:20
S109	1	"5301296".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:17
S108	1	"5638382".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:16
S107	1	"6101578".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:16
S106	1	"5638382".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:13
S105	1	"6115789".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:13
S104	1	"6145055".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:11
S103	1	"6351789".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:10
S102	1	"6658611".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:09
S101	1	"6732234".PN.	USPAT; USOCR	OR	ON	2007/01/24 11:08
S100	3	S99 and ((inject\$3 insert\$3 transmit\$4) near4 (fault error "bad bit"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/29 11:47
S99	62	S98 and ("built-in-self-test" "built-in\$1self- test" BIST "self-test")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/29 11:47

S95	3	S94 and ((inject\$3 insert\$3 transmit\$4) near4 (fault error "bad bit"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/29 11:47
S96	2	"6539503".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:54
S94	50	S93 and ("built-in-self-test" "built-in\$1self- test" BIST "self-test")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:49
S93	97	S92 and (714/710,711,718,719,733 365/200,201).cls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:49
S92	1828	(JTAG with (controller host processor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:49
S90	50	S89 and ("built-in-self-test" "built-in\$1self- test" BIST "self-test")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/01 11:41

S91	7	S89 and ((programmable \$2configurable) near3 ("built-in-self-test" "built-in\$1self-test" BIST "self-test"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:59
S89	97	S88 and (714/710,711,718,719,733 365/200,201).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:58
S87	91	S86 and (714/710,711,718,719,733 365/200,201).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:58
S79	18	((("built-in-self-test" "built-in\$1self-test" BIST "self-test") and (((plurality multiple) near2 control\$4 near2 signals) same (mux\$3 multiplex\$2 selector)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:58
S88	1828	(JTAG with (controller host processor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:57
S86	1179	JTAG with controller	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:57

S78	10617	(714/710,711,718,719,733 365/200,201). ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:57
S85	2	("5668818").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/31 16:56
S84	11	((("built-in-self-test" "built-in\$1self-test" BIST "self-test") same ((test\$3 near mode) with (((test scan) near enable) allow interlock inter-lock)) same (mux\$3 multiplex\$2 selector))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:46
S83	78	((("built-in-self-test" "built-in\$1self-test" BIST "self-test" test) same ((test\$3 near mode) with (test near enable)) same (mux\$3 multiplex\$2 selector))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:44
S82	661	((("built-in-self-test" "built-in\$1self-test" BIST "self-test" test) same (mode with enable) same (mux\$3 multiplex\$2 selector))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:41
S81	14	S79 not S80	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:03

S80	4	S78 and S79	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:03
S77	1	((("built-in-self-test" "built-in\$1self-test" BIST "self-test") same (((plurality multiple) near2 control\$4 near2 signals) with (mux\$3 multiplex\$2 selector)) and (memory \$2RAM))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 17:00
S75	25	S74 and ((built-in-self-test or built-in\$1self-test or BIST) same (control near4 signal mode) same ((programmable or control\$4 or selectable) near4 (MUX or multiplex\$2)) and (memory or \$2RAM or (plurality near2 addressable near2 memory near2 locations)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 16:59
S74	1082	(714/710,711,718,719,733).ccls. and interface	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 16:58
S76	6	((("built-in-self-test" "built-in\$1self-test" BIST "self-test") same (((plurality multiple) near4 control\$4 near3 signal) with (mux\$3 multiplex\$2 select\$3)) and (memory \$2RAM))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 16:57
S1	89	((built-in-self-test or built-in\$1self-test or BIST) same (control near4 signal mode) same ((programmable or control\$4 or selectable) near4 (MUX or multiplex\$2)) and (memory or \$2RAM or (plurality near2 addressable near2 memory near2 locations)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 17:41

S73	44	((714/711, "733".ccls.) and interface and @py<"2001")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 17:40
S68	22	(programmable near5 (built-in-self-test or built-in\$1self-test or BIST)) and ASIC	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 13:34
S72	2	((714/711, "733".ccls.) and (interface same BIST) and @py<"2001")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 09:22
S71	24343983	((714/711, "733".ccls.) and (interface same BIST) @py<"2001")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 09:21
S70	221	714/711.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/18 09:18
S69	665	714/733.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 15:14

S67	58	(program\$5 near5 (built-in-self-test or built-in\$1self-test or BIST)) and ASIC	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:48
S13	5	((program\$5 near5 (built-in-self-test or built-in\$1self-test or BIST)) and (MUX or multiplex \$2) and ((input/output or I/O) near2 controller))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:47
S66	630043	((built-in-self-test or built-in\$1self-test or BIST) same ((parallel concurrent) near4 testing)) same memory \$2RAM)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:39
S65	32	((built-in-self-test or built-in\$1self-test or BIST) same (parallel near4 testing)) same memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:37
S64	69	((built-in-self-test or built-in\$1self-test or BIST) same (parallel near4 testing)) and memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:27
S63	261	((built-in-self-test or built-in\$1self-test or BIST) same parallel) and memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:24

S62	261	((built-in-self-test or built-in\$1self-test or BIST) same parallel) and memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:23
S61	308	(built-in-self-test or built-in\$1self-test or BIST) same parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:19
S60	1	((US-6707718-\$ or US-5987632-\$ or US-5878051-\$ or US-6457141-\$ or US-6408413-\$ or US-6169418-\$ or US-6208477-\$ or US-5784382-\$ or US-5355369-\$ or US-5258985-\$ or US-5872793-\$ or US-5982681-\$).did. or (US-20020194557-\$ or US-20020174394-\$ or US-20020056063-\$).did.) and (I/O near2 controller)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 14:14
S59	15	(US-6707718-\$ or US-5987632-\$ or US-5878051-\$ or US-6457141-\$ or US-6408413-\$ or US-6169418-\$ or US-6208477-\$ or US-5784382-\$ or US-5355369-\$ or US-5258985-\$ or US-5872793-\$ or US-5982681-\$).did. or (US-20020194557-\$ or US-20020174394-\$ or US-20020056063-\$).did.	US-PGPUB; USPAT	OR	OFF	2004/06/17 14:13
S58	0	US-09927042\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:42

S57	0	US-09927042-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:42
S56	0	09927042-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:41
S55	2	"6594739".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:41
S54	2	"6578126".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:39
S53	2	"6636933".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:36
S52	75	Attaway.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:34

S51	75	Attaway\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:25
S50	2	Attaway-Brett\$.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:13
S17	0	"Attaway-Brett-W\$.ini"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/17 09:13
S49	64	(external\$2 near4 (program\$5 or select\$4 or control\$4) near5 (multiplex\$2 or MUX)) and (built-in-self-test or built-in\$1self-test or BIST)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:40
S3	37	((built-in-self-test or built-in\$1self-test or BIST) same (control near4 signal mode) same ((programmable or control\$4 or selectable) near4 (MUX or multiplex\$2)) and (interface near4 (logic module device control \$3)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:39
S48	1454	external\$2 near4 (program\$5 or select\$4 or control\$4) near5 (multiplex\$2 or MUX)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:38
S47	1	"4853843".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:35

S46	1	"4888772".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:34
S45	1	"4903266".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:34
S44	1	"5032979".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:34
S43	1	"5089958".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:34
S42	1	"5089958".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:33
S41	1	"5093787".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:33
S40	1	"5107501".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:33
S39	1	"5138619".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:32
S38	1	"5146573".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:32
S37	1	"5173906".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:32
S36	1	"5202969".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:31
S35	1	"5222066".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:31
S34	1	"5222224".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:29
S33	1	"5032979".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:29
S32	1	"4969148".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:28

S31	1	"5224101".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:26
S30	1	"5307484".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:26
S29	1	"5173906".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:24
S28	1	"4724380".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:21
S27	1	"4701920".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:21
S26	1	"4433413".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:20
S25	1	"5138619".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:19
S24	1	"5164665".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:18
S23	1	"5184067".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:18
S22	1	"5230000".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:16
S21	1	"5258985".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:15
S20	1	"5258985".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:11
S19	1	"5301199".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:11
S18	1	"5355369".PN.	US-PGPUB; USPAT	OR	ON	2004/06/16 17:08

S16	0	"Attaway-Brett-W.ini"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:06
S15	2	Attaway.in. and BIST	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:05
S14	75	Attaway.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 17:05
S12	1	((programmable near5 (built-in-self-test or built-in\$1self-test or BIST)) and (MUX or multiplex\$2) and ((input/output or I/O or disk) near2 controller))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 16:13
S8	124	((built-in-self-test or built-in\$1self-test or BIST) and (MUX or multiplex\$2) and (input/output or I/O or disk) near2 controller))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 16:04
S11	3	((built-in-self-test or built-in\$1self-test or BIST) and (SJT or system\$1under\$1test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 14:18

S10	0	(((built-in-self-test or built-in\$1self-test or BIST) and (MUX or multiplex\$2) and (input/output or I/O or disk) near2 controller))) and SUT	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 14:17
S9	1	(((built-in-self-test or built-in\$1self-test or BIST) and (MUX or multiplex\$2) and (input/output or I/O or disk) near2 controller))) and ((built-in-self-test or built-in\$1self-test or BIST) and disk).ab,ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 14:17
S7	31	(((built-in-self-test or built-in\$1self-test or BIST) same (MUX or multiplex\$2) and (input/output or I/O or disk) near2 controller)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 14:15
S6	0	(((built-in-self-test or built-in\$1self-test or BIST) same (MUX or multiplex\$2) and ((input/output or I/O or disk) near2 controller)) and host near4 controller and disk near4 storage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 13:48
S5	0	(((built-in-self-test or built-in\$1self-test or BIST) same (MUX or multiplex\$2) and (interface near4 (logic module device control \$3)) same ((input/output or I/O or disk) near2 controller)) and host near4 controller and disk near4 storage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 13:47
S4	1	((built-in-self-test or built-in\$1self-test or BIST) same (control near4 signal mode) same (MUX or multiplex\$2) and (interface near4 (logic module device control\$3)) same ((input/output or I/O) near2 controller))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 13:44

S2	29	((built-in-self-test or built-in\$1self-test or BIST) same (control near4 signal mode) same ((programmable or control\$4 or selectable) near4 (MUX or multiplex\$2)) and (memory or \$2RAM or (plurality near2 addressable near2 memory near2 locations)) and (external near6 control))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/16 13:01
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